

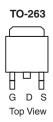
STB120NF10-VB Datasheet N-Channel 100-V (D-S) MOSFET

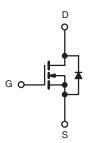
PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)			
100	0.010 at V _{GS} = 10 V	100			
	0.023 at $V_{GS} = 4.5 \text{ V}$	85			

FEATURES

- Trench Power MOSFET
- 175 °C Maximum Junction Temperature
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted					
Parameter			Limit	Unit	
Drain-Source Voltage		V_{DS}	100	V	
Gate-Source Voltage			± 20	V	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	. I _D	100	A	
	T _C = 125 °C		75 ^a		
Pulsed Drain Current	I_{DM}	300	A		
Avalanche Current	L = 0.1 mH	I _{AS}	75		
Single Pulse Avalanche Energy ^b	L = 0.1 IIII1	E _{AS}	280	mJ	
Maximum Power Dissipation ^b	T _C = 25 °C (TO-220AB and TO-263)	P _D	250 ^c	W	
	T _A = 25 °C (TO-263) ^d	ט י	3.75	**	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Limit	Unit		
Junction-to-Ambient	PCB Mount (TO-263) ^d	R _{thJA}	40	°C/W		
Junction-to-Ambient	Free Air (TO-220AB)	' 'thJA	62.5			
Junction-to-Case		R _{thJC}	0.6			

Notes:

- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			
Gate-Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2		4	V
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
		V _{DS} = 100 V, V _{GS} = 0 V			1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V, T _J = 125 °C			50	μΑ
		V _{DS} = 100 V, V _{GS} = 0 V, T _J = 175 °C			250	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} = \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α
		V _{GS} = 10 V, I _D = 30 A		0.010		
	D	V _{GS} = 4.5 V, I _D = 20 A		0.023		0
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V, I _D = 30 A, T _J = 125 °C		0.020		Ω
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 175 ^{\circ}\text{C}$		0.030		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 30 A	25			S
Dynamic ^b						
Input Capacitance	C _{iss}			6550		pF
Output Capacitance	C _{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		665		
Reverse Transfer Capacitance	C _{rss}			265		
Total Gate Charge ^c	Q _g			105	160	
Gate-Source Charge ^c	Q_gs	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 85 \text{ A}$		17		nC
Gate-Drain Charge ^c	Q_{gd}			23		
Turn-On Delay Time ^c	t _{d(on)}			12	25	
Rise Time ^c	t _r	$V_{DD} = 50 \text{ V}, R_{L} = 0.6 \Omega$		90	135	
Turn-Off DelayTime ^c	t _{d(off)}	$I_D \cong 85 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 2.5 \Omega$		55	85	ns
Fall Time ^c	t _f	1		130	195	
Source-Drain Diode Ratings and Char	racteristics T _C	= 25 °C ^b				
Continuous Current	I _S				85	^
Pulsed Current	I _{SM}				240	Α
Forward Voltage ^a	V _{SD}	I _F = 85 A, V _{GS} = 0 V		1.0	1.5	٧
Reverse Recovery Time	t _{rr}			85	140	ns
Peak Reverse Recovery Current	I _{RM(REC)}	I _F = 50 A, dI/dt = 100 A/μs		4.5	7	Α
Reverse Recovery Charge	Q _{rr}	1		0.17	0.35	μC

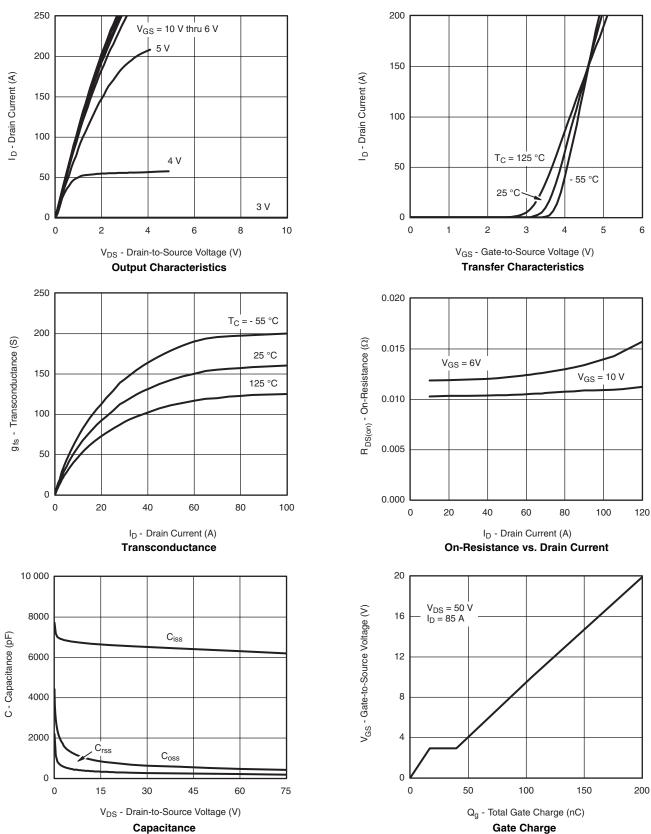
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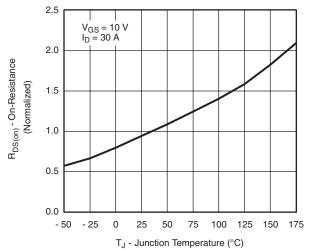


TYPICAL CHARACTERISTICS $T_A = 25 \, ^{\circ}C$, unless otherwise noted

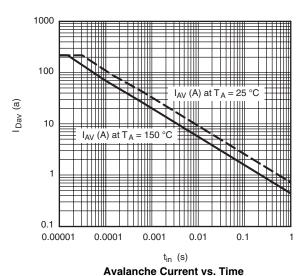




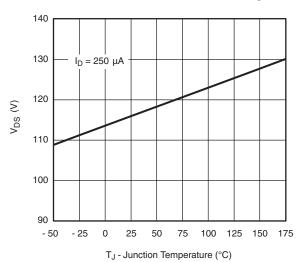
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On-Resistance vs. Junction Temperature



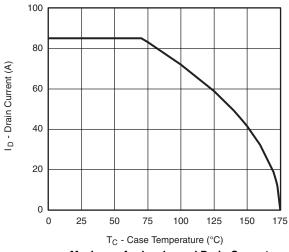
Source-Drain Diode Forward Voltage

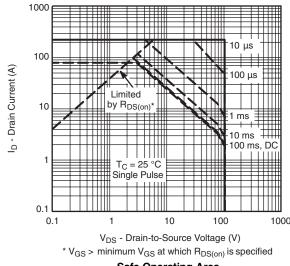


T_J - Drain-Source Breakdown vs. Junction-Temperature

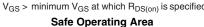


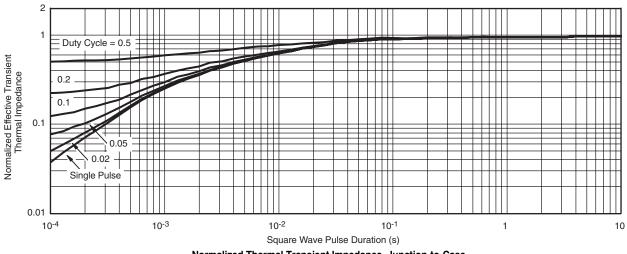
THERMAL RATINGS





Maximum Avalanche and Drain Current vs. Case Temperature





Normalized Thermal Transient Impedance, Junction-to-Case

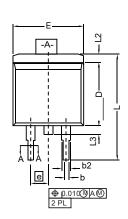


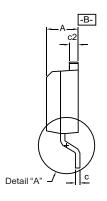
MILLIMETERS

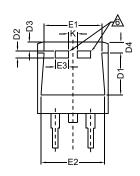
MAX.

MIN.

TO-263 (D²PAK): 3-LEAD







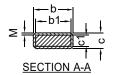
INCHES

MAX.

MIN.



DETAIL A (ROTATED 90°)



C
С

DIM.

Α		0.160	0.190	4.064	4.826
b		0.020	0.039	0.508	0.990
b1		0.020	0.035	0.508	0.889
b2		0.045	0.055	1.143	1.397
С*	Thin lead	0.013	0.018	0.330	0.457
	Thick lead	0.023	0.028	0.584	0.711
c1	Thin lead	0.013	0.017	0.330	0.431
CI	Thick lead	0.023	0.027	0.584	0.685
	c2	0.045	0.055	1.143	1.397
	D	0.340	0.380	8.636	9.652
	D1	0.220	0.240	5.588	6.096
	D2	0.038	0.042	0.965	1.067
	D3	0.045	0.055	1.143	1.397
D4		0.044	0.052	1.118	1.321
	E	0.380	0.410	9.652	10.414
	E1	0.245	-	6.223	-
	E2	0.355	0.375	9.017 9.5	
	E3	0.072	0.078	1.829	1.981
е		0.100 BSC		2.54 BSC	
K		0.045	0.055	1.143	1.397
L		0.575	0.625	14.605	15.875
L1		0.090	0.110	2.286	2.794
L2		0.040	0.055	1.016	1.397
	L3	0.050	0.070	1.270	1.778
	L4	0.010 BSC		0.254 BSC	
	M	_	0.002	_	0.050

ECN: T13-0707-Rev. K, 30-Sep-13

DWG: 5843

Note

- 1. Plane B includes maximum features of heat sink tab and plastic.
- 2. No more than 25 % of L1 can fall above seating plane by $\;$ max. 8 mils.
- 3. Pin-to-pin coplanarity max. 4 mils.
- 4. *: Thin lead is for SUB, SYB.
 Thick lead is for SUM, SYM, SQM.
- 5. Use inches as the primary measurement.

 This feature is for thick lead.



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